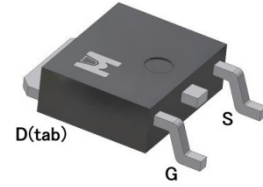


N-Channel Logic Level Enhancement Mode Field Effect Transistor

Product Summary:

BV <sub>DSS</sub>	250V
R <sub>DS(on)</sub> (MAX.)	1 Ω
I <sub>D</sub>	4.4A



UIS, R<sub>g</sub> 100% Tested

Pb-Free Lead Plating & Halogen Free



ABSOLUTE MAXIMUM RATINGS (T<sub>C</sub> = 25 °C Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Gate-Source Voltage		V <sub>GS</sub>	±20	V
Continuous Drain Current	T <sub>C</sub> = 25 °C	I <sub>D</sub>	4.4	A
	T <sub>C</sub> = 100 °C		2.6	
Pulsed Drain Current <sup>1</sup>		I <sub>DM</sub>	17.6	
Avalanche Current		I <sub>AS</sub>	1	
Avalanche Energy	L = 3mH, I <sub>D</sub> =1A, R <sub>G</sub> =25Ω	E <sub>AS</sub>	1.5	mJ
Repetitive Avalanche Energy <sup>2</sup>	L = 1mH	E <sub>AR</sub>	0.5	
Power Dissipation	T <sub>C</sub> = 25 °C	P <sub>D</sub>	29	W
	T <sub>C</sub> = 100 °C		11	
Operating Junction & Storage Temperature Range		T <sub>j</sub> , T <sub>stg</sub>	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	R <sub>θJC</sub>		4.2	°C / W
Junction-to-Ambient	R <sub>θJA</sub>		62.5	

<sup>1</sup>Pulse width limited by maximum junction temperature.

<sup>2</sup>Duty cycle ≤ 1%



ELECTRICAL CHARACTERISTICS ( $T_c = 25\text{ }^\circ\text{C}$ , Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 10mA$	250			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	1	2	3	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0V, V_{GS} = \pm 20V$			$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 200V, V_{GS} = 0V$			1	$\mu A$
		$V_{DS} = 200V, V_{GS} = 0V, T_J = 125\text{ }^\circ\text{C}$			25	
On-State Drain Current <sup>1</sup>	$I_{D(ON)}$	$V_{DS} = 10V, V_{GS} = 10V$	4.4			A
Drain-Source On-State Resistance <sup>1</sup>	$R_{DS(ON)}$	$V_{GS} = 10V, I_D = 2.2A$		0.82	1.0	$\Omega$
		$V_{GS} = 5V, I_D = 1.1A$		0.90	1.1	
Forward Transconductance <sup>1</sup>	$g_{fs}$	$V_{DS} = 50V, I_D = 2.2A$		2.3		S
<b>DYNAMIC</b>						
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$		1224		pF
Output Capacitance	$C_{oss}$			27		
Reverse Transfer Capacitance	$C_{rss}$			23		
Gate Resistance	$R_g$	$V_{GS} = 15mV, V_{DS} = 0V, f = 1MHz$		2.0		$\Omega$
Total Gate Charge <sup>1,2</sup>	$Q_g$	$V_{DS} = 200V, V_{GS} = 10V,$ $I_D = 2.2A$		32		nC
Gate-Source Charge <sup>1,2</sup>	$Q_{gs}$			4		
Gate-Drain Charge <sup>1,2</sup>	$Q_{gd}$			8.1		
Turn-On Delay Time <sup>1,2</sup>	$t_{d(on)}$	$V_{DS} = 125V,$ $I_D = 1A, V_{GS} = 10V, R_G = 6\Omega$		10		nS
Rise Time <sup>1,2</sup>	$t_r$			65		
Turn-Off Delay Time <sup>1,2</sup>	$t_{d(off)}$			20		
Fall Time <sup>1,2</sup>	$t_f$			35		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (<math>T_c = 25\text{ }^\circ\text{C}</math>)</b>						
Continuous Current	$I_S$				4.4	A
Pulsed Current <sup>3</sup>	$I_{SM}$				17.6	
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = I_S, V_{GS} = 0V$			1.3	V
Reverse Recovery Time	$t_{rr}$	$I_F = 4.4A, di_F/dt = 100A / \mu S$		125		nS
Reverse Recovery Charge	$Q_{rr}$			500		nC

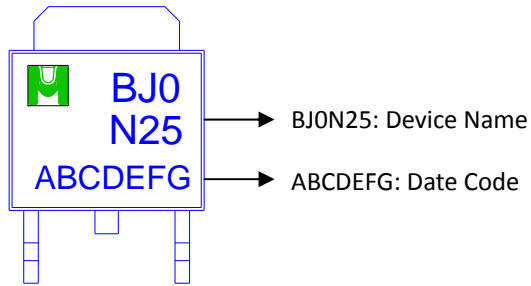
<sup>1</sup>Pulse test : Pulse Width  $\leq 300\text{ }\mu\text{sec}$ , Duty Cycle  $\leq 2\%$ .

<sup>2</sup>Independent of operating temperature.

<sup>3</sup>Pulse width limited by maximum junction temperature.

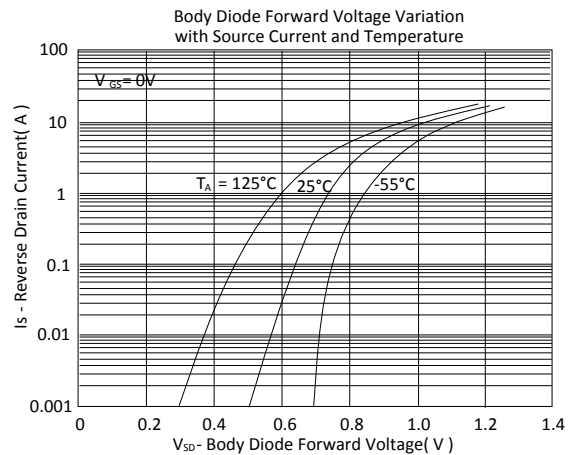
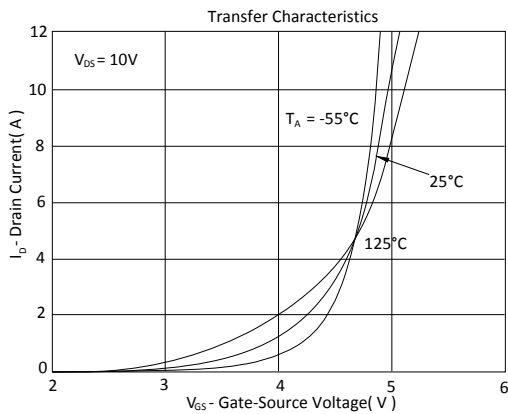
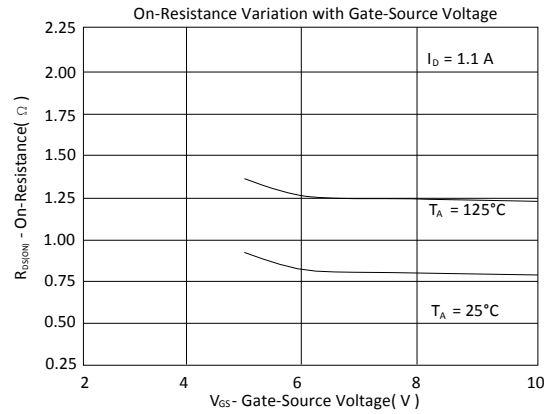
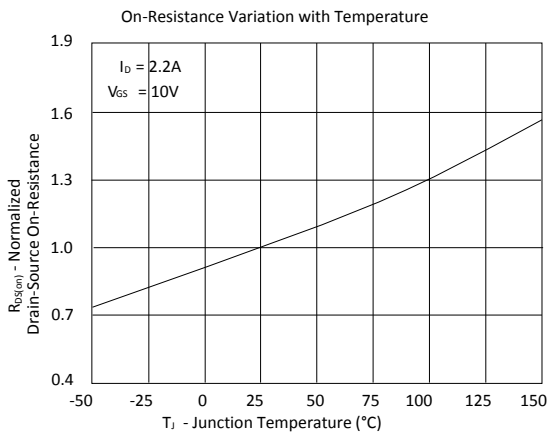
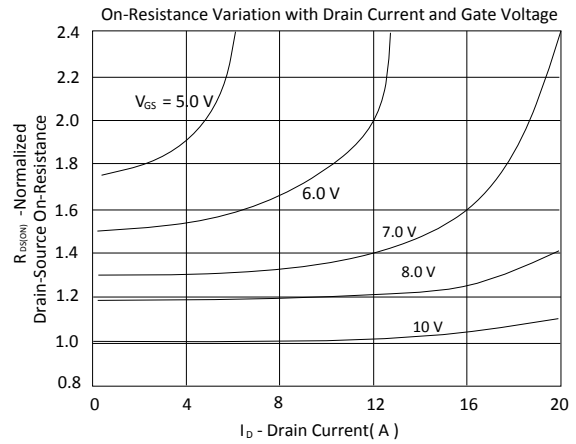
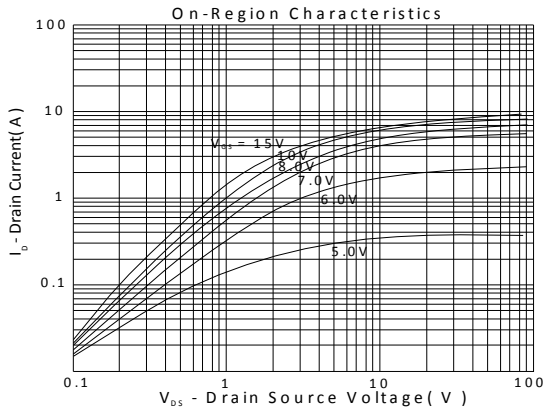
Ordering & Marking Information:

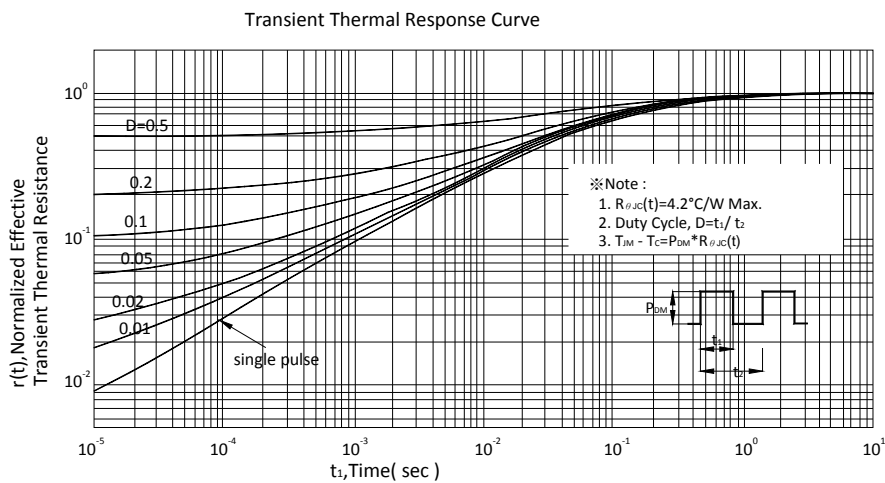
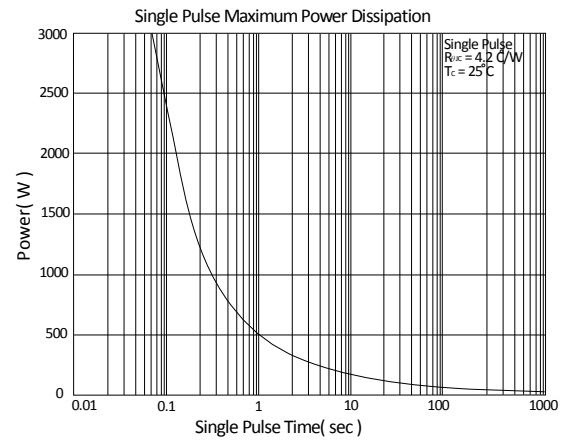
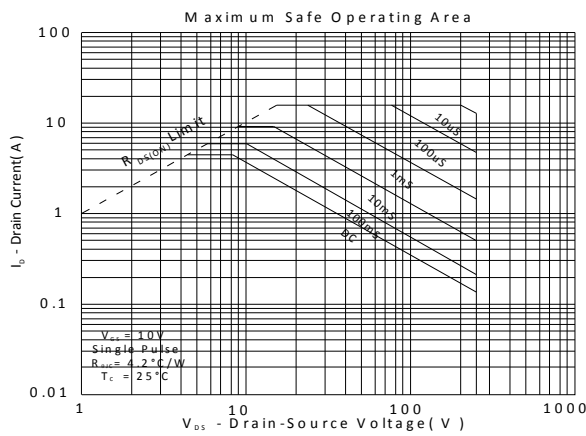
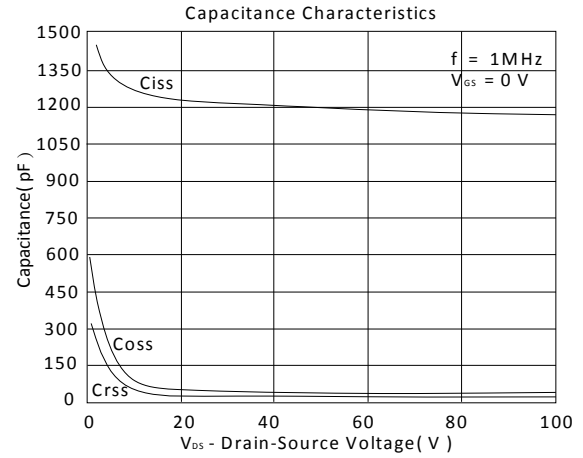
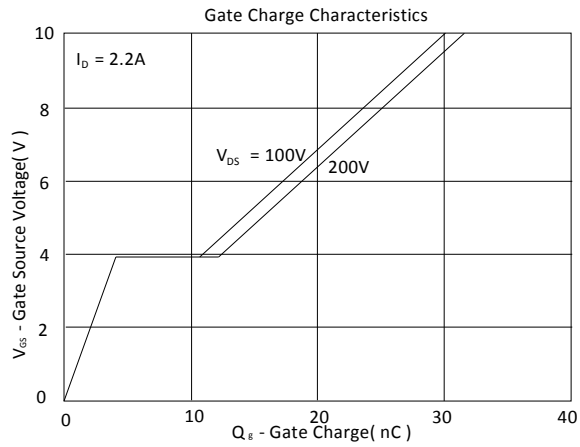
Device Name: EMBJ0N25A for DPAK (TO-252)





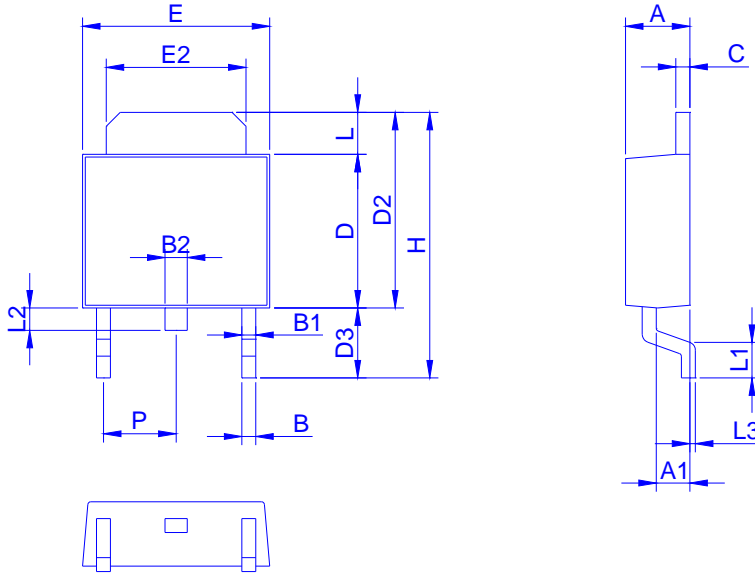
TYPICAL CHARACTERISTICS







Outline Drawing



Dimension in mm

Dimension	A	A1	B	B1	B2	C	D	D2	D3	E	E2	H	L	L1	L2	L3	P
Min.	2.10	0.95	0.30	0.40	0.60	0.40	5.30	6.70	2.20	6.40	4.80	9.20	0.89	0.90	0.50	0.00	2.10
Max.	2.50	1.30	0.85	0.94	1.00	0.60	6.20	7.30	3.00	6.70	5.45	10.15	1.70	1.65	1.10	0.30	2.50

Footprint

